

Notice of References Cited	Application/Control No. 10/816,150		Applicant(s)/Patent Under Reexamination ELFADEL, IBRAHIM M.	
	Examiner Shambhavi Patel		Art Unit 2128	Page 1 of 1

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*	B	US-6,188,974	02-2001	Cullum et al.	703/14
*	C	US-6,349,272	02-2002	Phillips, Joel	703/2
*	D	US-2003/0088394	05-2003	Min et al.	703/14
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NON-PATENT DOCUMENTS

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*	U	Elfadel et al. 'A Comparative Study of Two Transient Analysis Algorithms for Lossy Transmission Lines With Frequency-Dependent Data'. IEEE Transactions on Advanced Packaging, Vol. 25, No. 2, May 2002.
*	V	Jaijeet Royschowdhury. 'Automated Macromodel Generation for Electronic Systems'. August 2003.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.